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Fourth International Conference on Ellipsometry

Papers presented at the conference, but not included in the proceedings are as follows:

SPECTROSCOPIC ELLIPSOMETRY AND ESCA STUDIES OF THE PASSIVE FILM ON IRON

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ELLIPSOMETRY AT A MERCURY DROP

M.M.J. PIETERSE, M. SLUYTERS-REHBACH and J.H. SLUYTERS

Van 't Hoff Laboratory of Physical and Colloid Chemistry, State University, Utrecht, The Netherlands

THE EFFECT OF ANISOTROPY ON THE MEASUREMENT OF THE REFRACTIVE INDEX OF THIN TRANSPARENT FILMS

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and

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IMPROVING THE PRECISION OF ELLIPSOMETERS WITH OPTIMIZED PHOTON COUNTING APPLICATION TO COPPER TARNISHING

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